

# **SPIROC 2**

**User Guide (Draft)** 

Monday, 4<sup>th</sup> february 2009

### Introduction

The **CALICE** collaboration has designed an analogue HCAL prototype using Scintillating fibers read out by SiPM detectors. That 8000-channel physics prototype is currently in test beam at Fermilab. The read-out of that detector is ensured by an analogue front-end chip called FLC\_SIPM . A new front-end chip called **SPIROC** (standing for Silicon PM Integrated Read Out Chip) has been designed to read out the upcoming technological demonstrator foreseen in 2009.



#### 1 Presentation

**SPIROC** (SiPM Integrated Read Out Chip): Dedicated very front-end electronics for an ILC prototype hadronic calorimeter with SiPM readout.

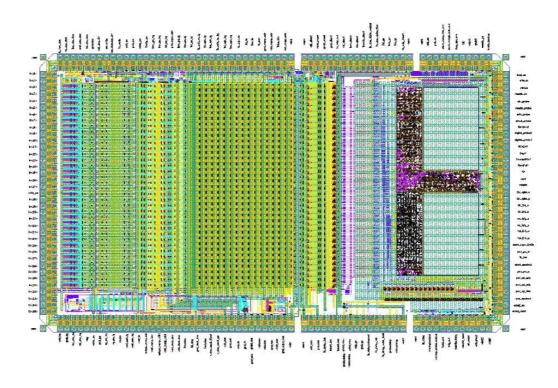
**SPIROC** is a dedicated very front-end electronics for an ILC prototype hadronic calorimeter with SiPM readout. It has been realized in 0.35m SiGe technology. It has been developed to match the requirements of large dynamic range, low noise, low consumption, high precision and large number of readout channels needed.

**SPIROC** is an auto-triggered, bi-gain, 36-channel ASIC which allows to measure on each channel the charge from one photoelectron to 2000 and the time with a 100ps accurate TDC.

An analog memory array with a depth of 16 for each is used to store the time information and the charge measurement. A 12-bit Wilkinson ADC has been embedded to digitize the analog memory contents (time and charge on 2 gains). The data are then stored in a 4kbytes RAM. A very complex digital part has been integrated to manage all theses features and to transfer the data to the DAQ.

**SPIROC 2** is the second iteration which corrects the bugs observed of the first version (**SPIROC 1**).





SPIROC layout



### 2 SPIROC description and global overview

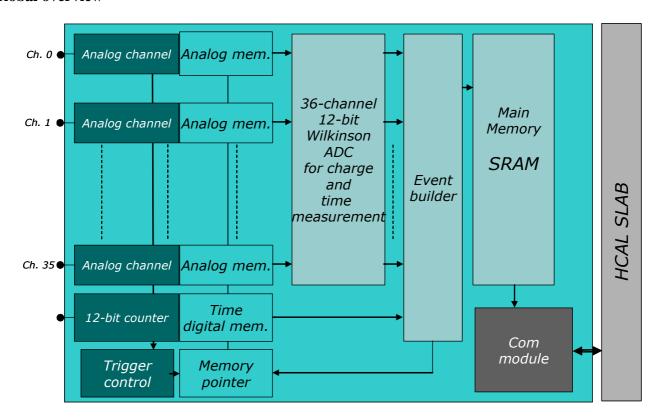
## **SPIROC** description

SPIROC main characteristics are the following:

- AMS SiGe 0.35µm technology
- $32\text{mm}^2$  (4.2mm × 7.2mm) area
- 5V/3.5V power supply
- 25µW per channel (in idle mode)
- Package: CQFP240
- Internal input 8-bit DAC (0-5V) for SiPM gain adjustment
- Energy measurement:
  - 2 gains / 12 bit ADC 1 pe  $\rightarrow$  2000 pe
  - Variable shaping time from 50ns to 100ns
  - pe/noise ratio: 11
- Time measurement:
  - 1 TDC (12 bits) step~100 ps
  - pe/noise ratio on trigger channel : 24
  - Fast shaper: ~15ns
  - Auto-Trigger on ½ pe



### Global overview





# 3 Pinout

bi_ota_dac bi_ota_dac vref_ota_dac bo_ota_dac b_dac_8bits b_1nA_dac vssa NC n<0> n<1> n<2> n<3> n<4> n<5> n<6>	Power  Analogue Bias Analogue Bias Analogue Bias Analogue Bias Analogue Bias Power  Analogue Input Analogue Input Analogue Input Analogue Input	Analogue (8-bit Digital to Analogue Convertor) Ground 8-bit DAC OTA input stage bias current 8-bit DAC OTA reference bias voltage 8-bit DAC OTA output stage bias current 8-bit input DAC bias current 1 8-bit input DAC bias current 2 Analogue part Bulk Channel 0 to 17 inputs Channel 0 to 17 inputs	to GND to 4.5V to GND	To To To To To
vref_ota_dac bo_ota_dac bo_ota_dac b_dac_8bits b_1nA_dac vssa VC n<0> n<1> n<2> n<3> n<4> n<4> n<5>	Analogue Bias Analogue Bias Analogue Bias Analogue Bias Power  Analogue Input Analogue Input Analogue Input	8-bit DAC OTA reference bias voltage 8-bit DAC OTA output stage bias current 8-bit input DAC bias current 1 8-bit input DAC bias current 2 Analogue part Bulk Channel 0 to 17 inputs		To To To To
bo_ota_dac b_dac_8bits b_1nA_dac vssa NC n<0> n<1> n<2> n<3> n<4> n<5>	Analogue Bias Analogue Bias Analogue Bias Power  Analogue Input Analogue Input Analogue Input	8-bit DAC OTA output stage bias current 8-bit input DAC bias current 1 8-bit input DAC bias current 2 Analogue part Bulk Channel 0 to 17 inputs		To To To
b_dac_8bits b_1nA_dac vssa NC n<0> n<1> n<4> n<3> n<4> n<5>	Analogue Bias Analogue Bias Power  Analogue Input Analogue Input Analogue Input	8-bit input DAC bias current 1 8-bit input DAC bias current 2 Analogue part Bulk Channel 0 to 17 inputs	to GND	To To
b_1nA_dac vssa NC n<0> n<1> n<2> n<3> n<4>	Analogue Bias Power  Analogue Input Analogue Input Analogue Input	8-bit input DAC bias current 2 Analogue part Bulk Channel 0 to 17 inputs	to GND	То
vssa NC n<0> n<1> n<2> n<3> n<4> n<5>	Power  Analogue Input Analogue Input Analogue Input	Analogue part Bulk  Channel 0 to 17 inputs	to GND	-1
NC n<0> n<1> n<2> n<3> n<4>	Analogue Input Analogue Input Analogue Input	Channel 0 to 17 inputs	to GND	Top
n<0> n<1> n<2> n<3> n<4> n<5>	Analogue Input Analogue Input	·		
n<1> n<2> n<3> n<4> n<5>	Analogue Input Analogue Input	·		
n<2> n<3> n<4> n<5>	Analogue Input	Channel 0 to 17 inputs	1	Le
n<3> n<4> n<5>	•	onamic oto mpato		Le
n<4> n<5>	Analogue Innut	Channel 0 to 17 inputs		Le
n<5>	, maioguo mput	Channel 0 to 17 inputs		Le
	Analogue Input	Channel 0 to 17 inputs		Le
	Analogue Input	Channel 0 to 17 inputs		Le
	Analogue Input	Channel 0 to 17 inputs		Le
n<7>	Analogue Input	Channel 0 to 17 inputs		Le
n<8>	Analogue Input	Channel 0 to 17 inputs		Le
n<9>	Analogue Input	Channel 0 to 17 inputs		Le
n<10>	Analogue Input	Channel 0 to 17 inputs		Le
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n<12>	Analogue Input	Channel 0 to 17 inputs		Le
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	•	·		Le
	•			Le
		Channel 18 to 35 inputs		Le
	•		<u> </u>	Le
n<34>	•			Le
	Analogue Input	Channel 18 to 35 inputs		Le
n<35> <b>NC</b>	· — —		+	
	n<13> n<14> n<15> n<16> n<16> n<17> dda_pa n<18> n<19> n<20> n<21> n<22> n<23> n<23> n<24> n<25> n<26> n<27> n<26> n<27> n<28> n<27> n<28> n<29> n<30> n<31> n<30> n<31> n<35>	Analogue Input	Analogue Input Channel 0 to 17 inputs Analogue Input Channel 18 to 35 inputs	Analogue Input Channel 0 to 17 inputs  Analogue Input Channel 18 to 35 inputs



48	vdd_bg	Power	Analogue (BandGap) Power Supply	to 3.3V	Botto
49	gnd_bg	Power	Analogue (BandGap) Ground	to GND	Botto
50	ibo_ota_bg	Analogue Bias	BandGap OTA output stage bias current		Botto
51	vbg	Analogue Output	BandGap output		Botto
52	vdda_pa	Power	Analogue (PreAmplifiers) Power Supply	to 3.3V	Botto
53	gnd_pa	Power	Analogue (PreAmplifiers) Ground	to GND	Botto
54	vg_pa_hg	Analogue Bias	High Gain PreAmps bias voltage		Botto
55	vg_pa_lg	Analogue Bias	Low Gain PreAmps bias voltage		Botto
56	va_pa	Analogue Bias	Pre Amps bias voltage		Botto
57	vref_ssh_lg	Analogue Bias	Low Gain Slow Shapers bias voltage		Botto
58	vref_ssh_hg	Analogue Bias	High Gain Slow Shapers bias voltage		Botto
59	vref fs	Analogue Bias	Fast Shapers bias voltage		Botto
60	vslope_ramp_tdc	Analogue Bias	TDC bias voltage 1		Botto
61	vref_ramp_tdc	Analogue Bias	TDC bias voltage 2		Botto
62	vslope_ramp_wilki	Analogue Bias	ADC bias voltage 1		Botto
63	vref_ramp_wilki	Analogue Bias	ADC bias voltage 2		Botto
64	vref_dual_dac	Analogue Bias	10-bit dual DAC OTAs bias voltage		Botto
65	vdd_dual_dac	Power	Analogue (10-bit dual DAC) Power Supply	to 3.3V	Botto
66	ibo_dac	Analogue Bias	10-bit dual DAC OTAs Output stage bias	1 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2	Botto
67	ibi dac	Analogue Bias	10-bit dual DAC OTAs Input stage bias		Botto
68	gnd_dual_dac	Power	Analogue (10-bit dual DAC) Ground	to GND	Botto
69	iref_dac	Analogue Bias	10-bit dual DAC bias current		Botto
70	v_dac_seuil_discri	Analogue Output	10-bit dual DAC output 1 (Trigger Discriminator Threshold)		Botto
71	v_dac_seuil_gs	Analogue Output	10-bit dual DAC output 2 (Gain Selection Discriminator Threshold)		Botto
72	vdd ssh	Power	Analogue (Slow Shaper) Power Supply	to 3.3V	Botto
73	gnd_ssh	Power	Analogue (Slow Shaper) Ground	to GND	Botto
74	vdd fs	Power	Analogue (Fast Shaper) Power Supply	to 3.3V	Botto
75	gnd_fs	Power	Analogue (Fast Shaper) Ground	to GND	Botto
76	gnd_sca	Power	Analogue (Switched Capacitor Array) Ground	to GND	Botto
77	vdd_sca	Power	Analogue (Switched Capacitor Array) Power Supply	to 3.3V	Botto
78	vdd_tdc	Power	Analogue (Time to Digital Convertor) Power Supply	to 3.3V	Botto
79	gnd_tdc	Power			
80	vddd_sca	Power	SCA Digital part Power Supply	to 3.3V	Botto
81	gnd_capa_sca	Power	Analogue SCA capacitors Ground	to GND	Botto
82	vssa	Power	Analogue part Bulk	to GND	Botto
83	vssm	Power	Mixed part Bulk	to GND	Botto
84	vdd_adc	Power	Mixed (ADC Discriminator) Power Supply	to 3.3V	Botto
85	gnd_adc	Power	Mixed (ADC Discriminator) Ground	to GND	Botto
86	ib_delay_tdc	Analogue Bias	TDC delay cell bias current		Botto
87	ibias1_tdc	Analogue Bias	TDC ramp1 amplifier bias current		Botto
88	ibias2_tdc	Analogue Bias	TDC ramp2 amplifier bias current		Botto
89	gndd_delay	Power	Digital (Discriminator Delay) Ground	to GND	Botto
90	vddd_delay	Power	Digital (Discriminator Delay) Power Supply	to 3.3V	Botto
91	vdd_gs	Power	Mixed (Gain Selection) Power Supply	to 3.3V	Botto
92	gnd_gs	Power	Mixed (Gain Selection) Ground	to GND	Botto
93	ib_delay_channel	Analogue Bias	Channel trigger delay cell bias current		Botto
94	ib_delay_rst	Analogue Bias	SCA "Reset" Signal delay cell bias current		Botto
95	ib_delay_valid_hold	Analogue Bias	SCA "Valid Hold" delay cell bias current		Botto
96	•		•	to GND	Botto
90	gnda_delay	Power	Analogue (Discriminator Delay) Ground	to GND	סווטם



97	vdda_delay	Power	Analogue (Discriminator Delay) Power Supply	to 3.3V
98	vssm	Power	Mixed part Bulk	to GND
99	vssd	Power	Digital part Bulk	to GND
100	ib_otaq	Analogue Bias	Analogue outputs OTA bias	
101	analog_output	Analogue Output	SCA Analogue Output	
102	analog_probe_output	Analogue Output	Analogue Probe Output	
103	hold_ext	Digital Input	External channel trigger signal	Active ↑
104	srout_read	Digital Output	Read Register Output	'
105	resetb_delay	Digital Input	Delay cells reset signal	Active L
106	resetb_read	Digital Input	Read Register Reset	Active L
107	clk read	Digital Input	Read Register Clock	
108	srin_read	Digital Input	Read Register Input	
109	vddd2	Power	Digital (Digital ASIC) Power Supply	to 3.3V
110	vddd1	Power	Digital (LVDS receivers & digital glue) Power Supply	to 3.3V
111	vssd	Power	Digital part Bulk	to GND
112	NC			
113	digital_probe2	Digital Output	Digital Probe 2 Output	
114	digital_probe1	Digital Output	Digital Probe 1 Output	
115	pwr_on_sca	Digital Input	SCA Power Pulsing Control	Active H
116	trig_ext	Digital Input	External forced OR36 signal	Active ↑
117	pwr_on_dac	Digital Input	DAC Power Pulsing Control	Active H
118	pwr_on_adc	Digital Input	ADC Power Pulsing Control	Active H
119	pwr_on_a	Digital Input	Analogue Part Power Pulsing Control	Active H
120	pwr_on_d	Digital Input	Digital Power Pulsing Control	Active H
121	ib_rec	Analogue Bias	LVDS receiver bias current	
122	StartAcq	Digital Input	Start & maintain acquisition on analogue memory	Active H
123	Val_Evt_p	Digital (LVDS)	doe dieeri	A ative I
124	Val_Evt_n	Input	v_dac_discri	Active L
125	Raz_Chn_p	Digital (LVDS)	Francisco Anglesia Caluma	A ationa 1.1
126	Raz_Chn_n	Input	Erase active Analogue Column.	Active H
127	CK_5M_p	Digital (LVDS)	Slow Clock (Acquisition = 5MHz , ReadOut =	
128	CK_5M_n	Input	1MHz)	
129	CK_40M_p	Digital (LVDS)		
130	CK_40M_n	Input	40MHz Clock	
131	vssd	Power	Digital part Bulk	to GND
132	resetb	Digital Input	Reset ASIC digital part	Active L
133	rtn	Power	Open Collector Ground	to GND
		Digital OC		Open
134	Dout1b	Output	Data Serial Output	Collector
135	Dout2b	Digital OC Output	Data Serial Output	Open Collector
136	TransmitOn1b	Digital OC Output	Active data readout	Open Collector / Active H
137	TransmitOn2b	Digital OC Output	Active data readout	Open Collector / Active H
138	ChipSatb	Digital OC Output	Analogue memory full / Acq stopped by DAQ	Open Collector / Active H
139	start_convb	Digital Input	Start conversion signal	Active L
140	start_readout1	Digital Input	Digital RAM start reading signal	Active H



141	start_readout2	Digital Input	Digital RAM start reading signal	Active H	F
142	end_readout1	Digital Output	Digital RAM end reading signal	Active H	F
143	end_readout2	Digital Output	Digital RAM end reading signal	Active H	F
144	select	Digital Input	Select Slow Control Register (1) or Probe Register (0)		R
145	sr_rstb	Digital Input	Selected Register Reset	Active L	R
146	sr_ck	Digital Input	Selected Register Clock	Active ↑	R
147	sr_in	Digital Input	Selected Register Input		F
148	sr_out	Digital Output	Selected Register Output		F
149	sr_load	Digital Input	Slow Control Register Load Signal	Active ↑	F
150	NC				
151	vssd	Power	Digital part Bulk	to GND	Top
152	holdb_backup	Digital Input	Backup Analogue Memory Hold Signal	Active L	-
153	resetb_pa	Digital Input	Charge PreAmp Reset Signal	Active L	-
154	gndd1	Power	Digital (LVDS receivers & Digital glue) Ground	to GND	-
155	vddd2	Power	Digital (Digital ASIC) Power Supply	to 3.3V	-
156	flag_tdc_ext	Digital Input	External charge or time SCA select command		-
157	start_rampb_adc_ext	Digital Input	External ADC Ramp Start Signal	Active L	-
158	start_ramp_tdc_ext	Digital Input	External TDC Ramp1 to Ramp2 Switch Signal	Active H	-
159	gnd_sc	Power	Digital (Slow Control Register) Ground	to GND	-
160	vdd_sc	Power	Digital (Slow Control Register) Power Supply	to 3.3V	-
161	vssd	Power	Digital part Bulk	to GND	-
162	vssm	Power	Mixed part Bulk	to GND	_
163	ib_adc_discri	Analogue Bias	ADC discriminator bias current		7
164	ibo_gs	Analogue Bias	Gain Selector output stage bias current		_
165	ibm_gs	Analogue Bias	Gain Selector middle stage bias current		-
166	ibi_gs	Analogue Bias	Gain Selector input stage bias current		_
167	ib_dac_4bits_fine	Analogue Bias	4-bit DAC fine adjustement bias current		-
168	ib_dac_4bits_coarse	Analogue Bias	4-bit DAC coarse adjustement bias current		-
169	ibomin_discri	Analogue Bias	Discriminator output stage minimum bias current		-
170	ibo_discri	Analogue Bias	Discriminator output stage bias current		
171	ibm_discri	Analogue Bias	Discriminator middle stage bias current		
172	ibi_discri	Analogue Bias	Discriminator input stage bias current		_
173	in_adc_ext	Analogue Input	ADC External input		_
174	gnd_discri	Power	Analogue (Discriminator) Ground	to GND	-
175	gndd_mask	Power	Digital (Mask & Discriminator) Ground	to GND	
176	vddd_mask	Power	Digital (Mask & Discriminator) Power Supply	to 3.3V	7
177	vdd_discri	Power	Analogue (Discriminator) Power Supply	to 3.3V	_
178	vssm	Power	Mixed part Bulk	to GND	7
179	vssa	Power	Analogue part Bulk	to GND	7
180	out_ramp_adc	Analogue Output	ADC ramp output		]
181	ibias_adc	Analogue Bias	ADC ramp amplifier bias current	40.2.21/	7
182	vdd_ramp_adc	Power	Analogue (ADC Ramp) Power Supply	to 3.3V	7
183	gnd_ramp_adc	Power	Analogue (ADC Ramp) Ground	to GND	7
184	ib_sca	Analogue Bias	SCA bias current		]
185	ibo_fs	Analogue Bias	Fast Shaper output stage bias		7
186	ibi_fs	Analogue Bias	Fast Shaper input stage bias		7
187	ib_suiv_fs	Analogue Bias	Fast Shaper follower bias current		1
188	ibo_ssh_hg	Analogue Bias	High Gain Slow Shaper output bias current		1
189	ibi_ssh_hg	Analogue Bias	High Gain Slow Shaper input bias current		7
190	ib_suiv_rc_hg	Analogue Bias	High Gain Slow Shaper follower bias current		7
191	ibo_ssh_lg	Analogue Bias	Low Gain Slow Shaper output bias current		

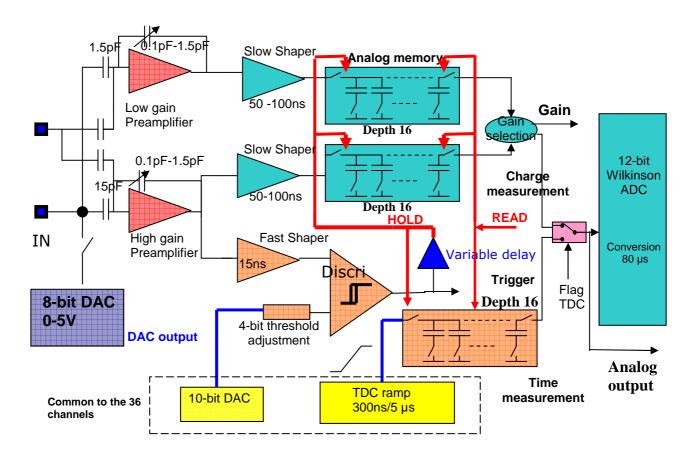


192	ibi_ssh_lg	Analogue Bias	Low Gain Slow Shaper input bias current		Тор
193	ib_suiv_rc_lg	Analogue Bias	Low Gain Slow Shaper follower bias current		Тор
194	ibi_pa_lg	Analogue Bias	Low Gain PreAmps input stage bias current		Top
195	ibo_pa_lg	Analogue Bias	Low Gain PreAmps output stage bias current		Тор
196	ibm_pa_lg	Analogue Bias	Low Gain PreAmps middle stage bias current		Тор
197	gnd_capa_ssh	Power	Analogue (Slow Shaper Capacitor) Ground	to GND	Тор
198	ibi_pa_hg	Analogue Bias	High Gain PreAmps input stage bias current		Тор
199	ibo_pa_hg	Analogue Bias	High Gain PreAmps output stage bias current		Тор
200	ibm_pa_hg	Analogue Bias	High Gain PreAmps middle stage bias current		Тор
201	ibmin_pa	Analogue Bias	Pre Amps input & output stage minimum bias current		Тор
202	vdda_pa	Power	Analogue (PreAmplifier) Power Supply	to 3.3V	Тор
203	gnd_pa	Power	Analogue (PreAmplifier) Ground	to GND	Тор
204	vdd_pa	Power	Analogue (PreAmplifier) Power Supply	to 3.3V	Тор
205	in_calib	Analogue Input	Calibration input		Тор
206	vdd_ota_dac_5V	Power	Analogue (8-bit DAC OTA) Power Supply	to 5V	Тор
207	sw_c15p	Digital Input	Short high gain PA input coupling capacitor Signal	Active H (Caution: 5 Volts)	Тор
208	vdd_dac_5V	Power	Analogue (8-bit Digital to Analogue Convertor) Power Supply	to 5V	Тор



#### 4 Spiroc Analog Part

The analogue core is composed of 36 channels embedding an input DAC for SiPM high voltage adjustment on 5V to tune gain channel by channel. Two preamplifiers allow the requested dynamic range and are followed by a trigger line made of a fast shaper and a discriminator. The charge measurement line is made of two variable slow shapers and two 16-depth SCAs. The block scheme of a channel is shown on the next figure.

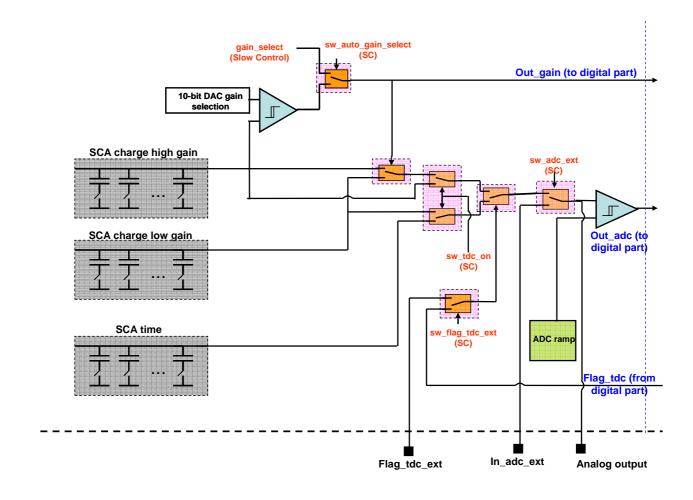




#### 5 Embedded ADC

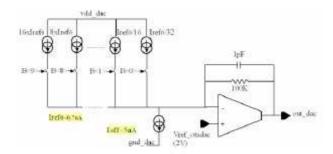
The ADC used in SPIROC is based on a Wilkinson structure. Its resolution is 12 bits. As the default accuracy of 12 bits is not always needed, the number of bits of the counter can be adjusted from 8 to 12 bits.

This type of ADC is particularly adapted to this application which needs a common analogue voltage ramp for the 36 channels and one discriminator for each channel. The ADC is able to convert 36 analogue values (charge or time) in one run (about  $100 \, \mu s$  at  $40 \, MHz$ ). If the SCA is full, 32 runs are needed (16 for charges and 16 for times).





### 6 Embedded DAC



Reference voltages all referred to an integrated bandgap.

 $I_{\text{ref0}}$  and  $I_{\text{off0}}$  can be changed thanks to an external resistor and are used to adjust the dynamic range of the dac.

- All Bits OFF => out\_dac=  $V_{ref\_dac}$ +100K\* $I_{off}$ =2V+500mV= 2.5V
- All Bits ON => out\_dac=  $2.5 (32*I_{ref0})*100k=260mV$

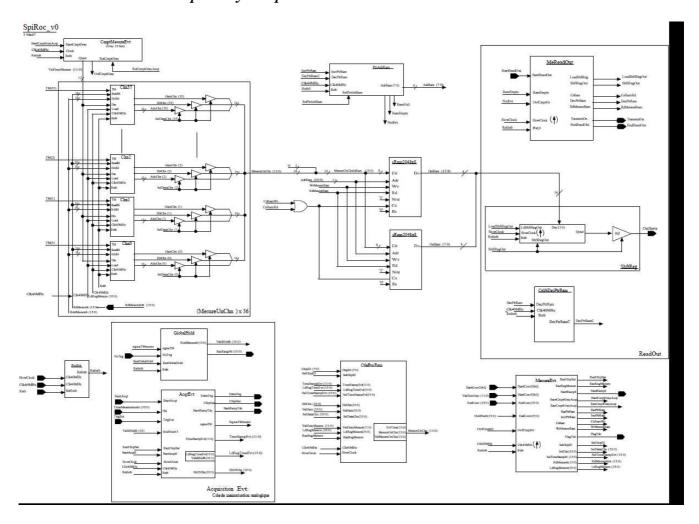
Two integrated 10-bit DAC to deliver threshold voltages of the 2 discriminators (trigger discriminator and gain selection discriminator).



### 7 Spiroc Digital Part

The system on chip has been designed to match the ILC beam structure. The complete readout process needs at least 3 different steps:

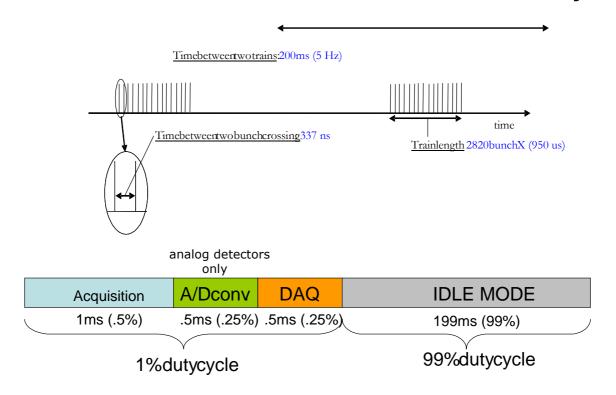
- a. acquisition phase
- b. conversion phase
- c. readout phase
- d. and possibly idle phase



The digital part of *SPIROC* is built around 3 modules which represent the different phases of the ILC working shown in the next figure.

The acquisition module permits to capture data during the bunch crossing train. Measure and Read-Out ones are activated during inter bunch crossing to convert and save data in the memory in a first step and to read out data to the external concentrator with a reduced numbers of lines.





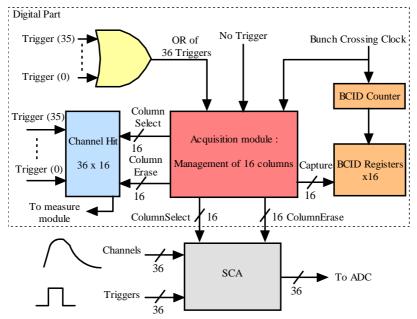
Digital part phases versus time.

Acquisition	A/D conversion	DAQ
When an event occurs:  • Charge is stored in analogue memory  • Time is stored in digital (coarse) and analogue (fine) memory  • Trigger is automatically rearmed at next coarse time flag (bunch crossing ID)  Depth of memory is 16	The data (charge and time) stored in the analogue memory are sequentially converted into digital data and stored in a SRAM.	The events stored in the RAM are readout through a serial link when the chip gets the token allowing the data transmission.  When the transmission is done, the token is transferred to the next chip.  256 chips can be read out through one serial link

### a. Acquisition module

This module given in the next figure allows to select the right column where analogue value should be stored

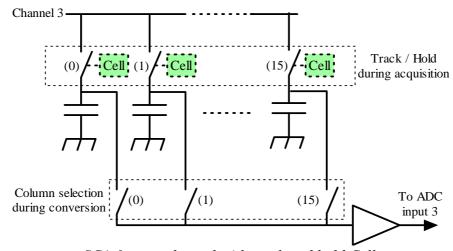




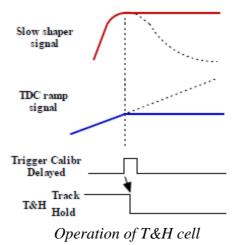
Detailed block diagram of acquisition module.

During idle mode, a capture window is open at the first empty column. When a trigger occurs, data can be captured in this column by means of a "Track and Hold Cell" inside the SCA..

When next bunch crossing occurs, it closes the capture window and selects the next column.



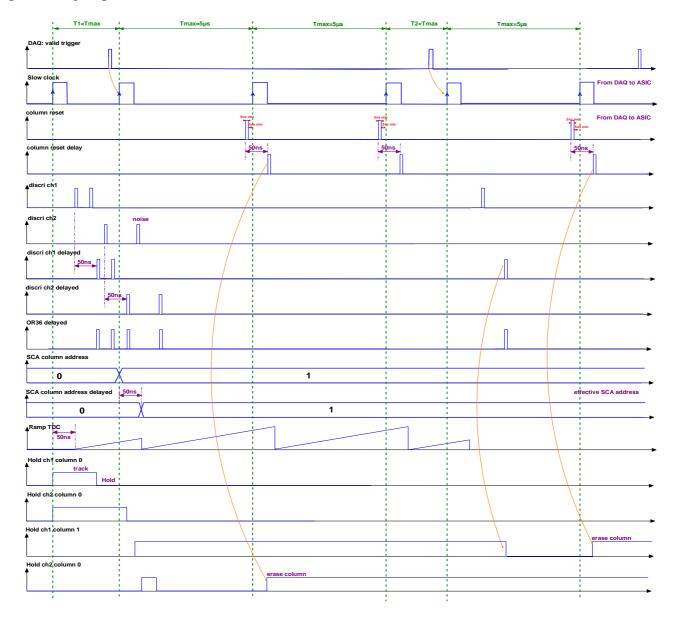
SCA for one channel with track and hold Cell.





An external signal is available to erase the present column named "No Trigger". It can be used to erase the column if a trigger was due to noise.

The Acquisition part has been developed with asynchronous cells to meet time and low consumption requirements. Besides, this allows no coupling between digital clock and analogue part during acquisition.

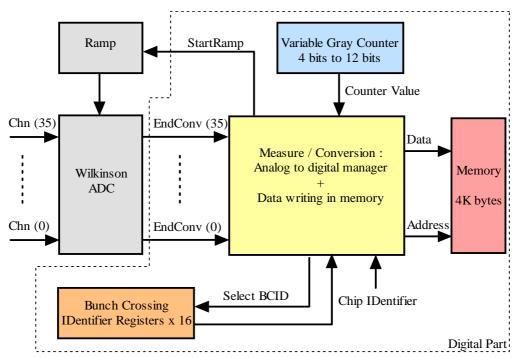


#### b. Measure module

The main purpose of this module is to convert analogue value stored in the SCA in digital ones.

The next figure represents the detailed block diagram of the measure and conversion module.





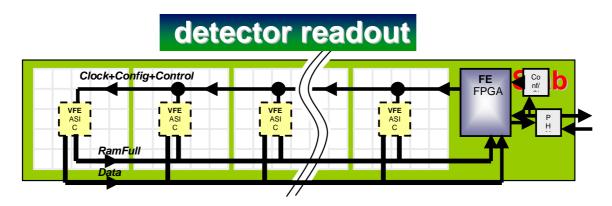
36 charges and 36 times stored in SCA must be converted for each column. That means 32 ADC conversions (16 charges and 16 times). When conversion is over, data are stored in the memory in order to start a new conversion.

As the default accuracy of 12 bits is not always needed for conversion, the number of bits of this counter can be adjusted from 4 to 12 bits.

#### c. Readout module

The Readout module permits to empty the memory where all data are stored. To minimize lines between board and external concentrator, data are transferred on a single line..

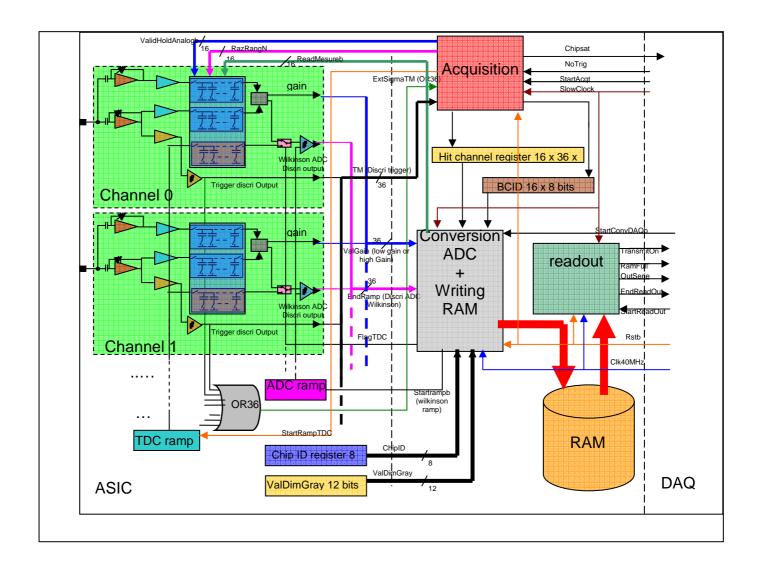
In the worst case, about 20K bits of data are transferred to the concentrator with a clock of 5 MHz. As the data line to the concentrator is common to all the daisy-chained ASICs, one ASIC can take the data line for a maximum of 4 ms.



### d. Idle mode

When all these operations are done, the chip goes to idle mode to save power. In the ILC beam structure 99 % of power can be saved.



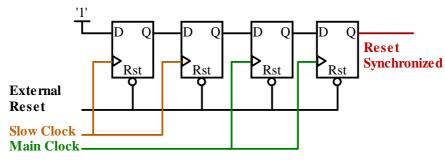




### 8 Master reset of digital part

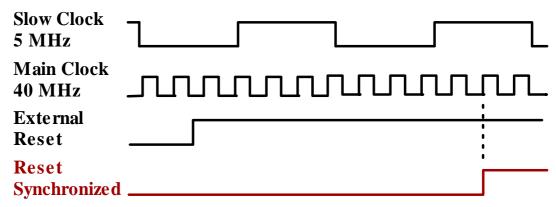
General Reset of the digital part is active low and synchronous with rising edge of Main Clock. It is active for the 2 clock domains (Slow Clock and Main Clock).

To prevent timing violation when Reset is released, it must be synchronised with the 2 clock domains. Reset logic is given below.



Master Reset logic

This circuit inserts latency when Reset is released (start of digital part). Latency is equal to 2 periods of Slow Clock + 2 periods of Main Clock (450 ns with 5 MHz and 40 MHz). This is shown in the next Figure.



Release of master reset



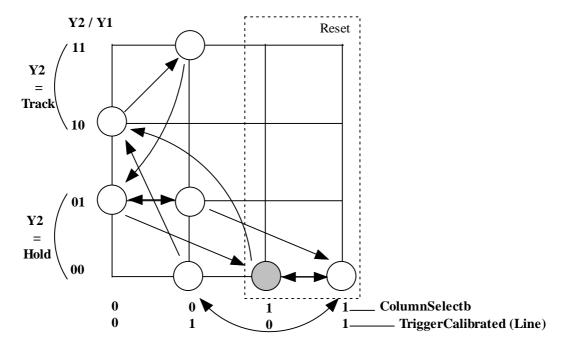
### 9 The Track & Hold digital cell

T&H cell allows to lock the capacitor value only when a calibrated trigger occurs within the selected column.

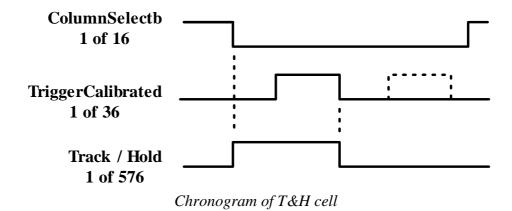
The hold of the capacitor is made when the trigger disappears.

The selected column is given by the acquisition module and the channel trigger gives the line.

The operation of the asynchronous cell is described below.



This operation above is the same as the chronogram in the next figure.





# 10 "Backup" track and hold

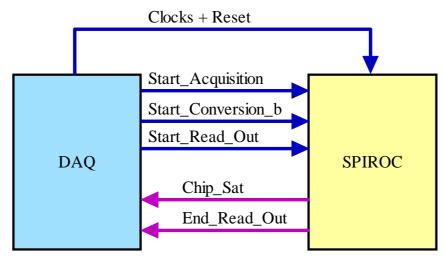
A "backup" track and hold is included in the chip. It consists is a basic 1-deep analog memory. This track and hold may be activated by slow control (sw\_sca\_backup).

The signal "Hold\_backupb" is used to store the signal. ("track" Hold\_backupb=1 and "hold" Hold\_backupb=0)



### 11 Link between DAQ and SPIROC

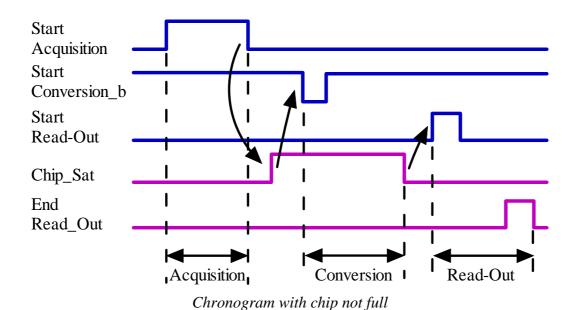
The 3 modules of the digitals parts are activated by signals from the DAQ. These signals are given below.



Main Signals between DAQ and SPIROC

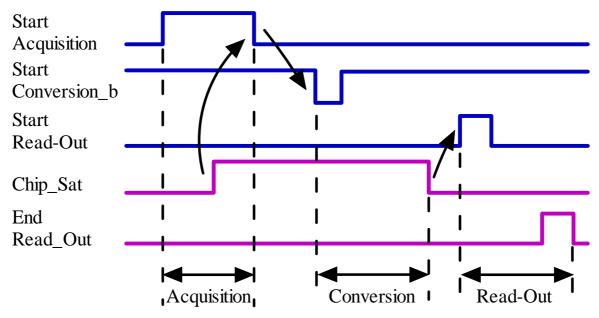
The rising edge of the Start\_Acquisition signal is the beginning of the acquisition phase for the digital part. The end of the acquisition is given by the falling edge of this signal.

The chronogram of the sequence is given below In this case, the DAQ stops the acquisition even if the chip is not full (end of bunch crossing for example). The falling edge of Chip\_Sat represents the end of the conversion.



Another case is possible when the chip is full during the acquisition phase. This is shown on next figure

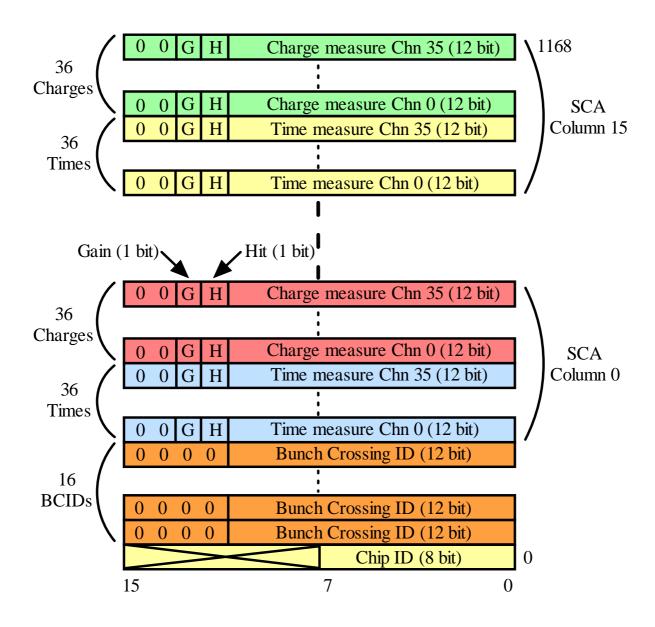




Chronogram with chip full



# 12 Spiroc RAM mapping





#### 13 Slow control and probe registers

2 shift registers are integrated and coupled: a probe register to select and watch different points in the chip and a Slow Control register to load serially the Slow control parameters.

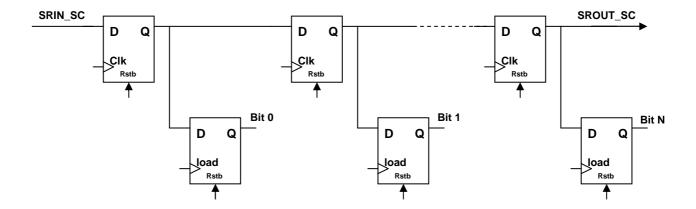
The probe register allows seeing different signals in the chip:

- ➤ 2 digital probe ("probe 1" and "probe 2") for digital signals
- ➤ 1 analog probe ("analog probe") for intermediate analog signals

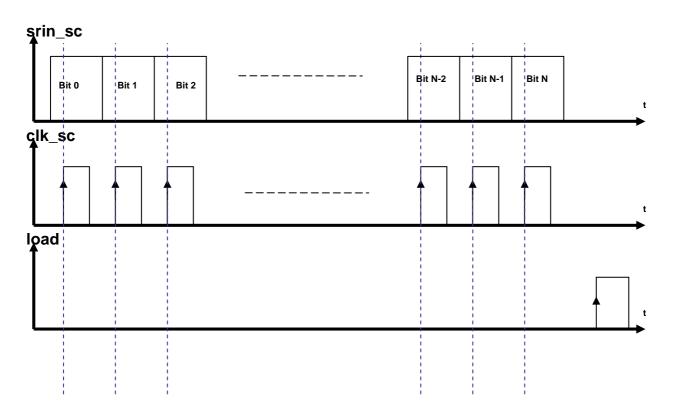
The data input (sr\_in), clock (sr\_clk) and reset (sr\_rstb) of these 2 registers are sent to the Slow Control or probe register inputs depending of the level of the external select signal. Unfortunatly, the reset of both registers is active low (rstb) and thus the Slow Ccontrol register is reseted when the select command is swithed from vdd to 0. It means that this **select command has to be set to vdd** and that the **Read register can't be used in SPIROC2**.

#### Slow control register

- One slow control register to load serially the 712 slow controls parameters:







Labview Register Name	bits	Register description	Subadd	ASIC Register Name
EC: Trig Ext (OR36)	1	Enable external trig_ext (OR36)	0	sw_trig_ext
EC: Flag TDC Ext	1	Enable external flag_tdc_ext signal	1	sw_flag_tdc_ext
		Enable external startb_ramp_adc		
EC: Start Ramp ADC Ext			2	sw_ramp_adc_ext
		Enable external start_ramp_tdc		
EC : Start Ramp TDC Ext	1	signal	3	sw_ramp_tdc_ext
		ADC Gray counter resolution		adc_res_register (gray counter) (12
GC : ADC Gray (12 bits)	12	register (from LSB to MSB)		bits)
GC : Chip ID (8 bits)	8	Chip ID (from LSB to MSB)	16	chip_ID_register (8 bits)
NC	5		24	
		ADC ramp slope (ramp slope 12, 10		
GC : ADC Ramp Slope	2	or 8 bits)	29	resolution adc
		Enable adc ramp current source		
PP: ADC Ramp Current Source	1	power pulsing	31	pwr_on_adc_ramp_current_source
		Enable adc ramp integrator power		
PP: ADC Ramp Integrator	1	pulsing	32	pwr_on_adc_ramp_integrator
		Input 8-bit DAC Data from channel		
T	22.4	0 to 35 – (DAC0DAC7 + DAC	00	
ID : Input 8-bit DAC	324	ON)	33	input_dac_8bits
CC - C	4	High gain preamp compensation	257	h-
GC : Capacitor HG PA Comp	4	capacitances commands (03) High gain preamp feedback	357	sw_pa_comp_hg
GC : Capacitor HG PA Fdbck	4	capacitances commands (03)	361	sw_pa_cf_hgb (active high)
GC. Capacitor HGTA Fubek	4	Low gain preamp feedback	301	sw_pa_ci_ngo (active nigh)
GC : Capacitor LG PA Fdbck	4	capacitances commands (30)	365	sw_pa_cf_lgb (active high)
Ge : Capacitor EG 1711 ubck		Low gain preamp compensation	000	sw_pa_cr_rgo (active ringin)
GC : Capacitor LG PA Comp	4	capacitances commands (30)	369	sw_pa_comp_lg
PP: Preamplifier	1	Enable preamp power pulsing		pwr_on_pa
		Disable charge preamp + Enable	0.0	T21
PA : PreAmp & Ctest config	72	test capacitor (from channel 0 to 35)	374	sw_pa_enable+ sw_pa_ctest_enable



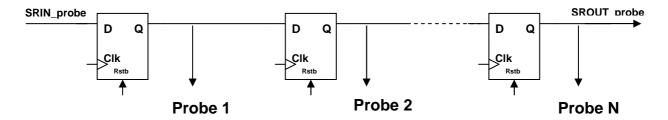
1	1 1	- · · · · · · · · · · · · · · · · · · ·		
	1	Enable low gain slow shaper	4.40	
PP: Low Gain SSh Follower	1	follower power pulsing	446	pwr_on_suiv_ssh_lg
	2	Low gain shaper time constant	4.47	1. (
GC : Time Constant LG Shaper	3	commands (20)	447	sw_rc_lg (active low)
	1	Enable low gain slow shaper power	450	1. 1.
PP: Low Gain Slow Shaper	1	pulsing	450	pwr_on_ssh_lg
DD. High Color CCh Eallannan	1	Enable high gain slow shaper	454	
PP: High Gain SSh Follower	I	follower power pulsing	451	pwr_on_suiv_ssh_hg
CC - Time Constant HC Shaner	2	High gain shaper time constant	450	avy no ha (active law)
GC : Time Constant HG Shaper	3	commands (20) Enable high gain slow shaper power	452	sw_rc_hg (active low)
PP: High Gain Slow Shaper	1	pulsing	155	num on sch ha
FF: Figh Gain Slow Shaper	1	Enable fast shaper follower power	400	pwr_on_ssh_hg
DD: Fact Change Fallower	1		156	nur on quiu fo
PP: Fast Shapers Follower	1	pulsing		pwr_on_suiv_fs
PP: Fast Shaper	1	Enable fast shaper power pulsing	457	pwr_on_fs
GC : backup SCA	1	Enable backup SCA		sw_sca_backup
PP: SCA	1	Enable SCA power pulsing	459	pwr_on_sca
		10-bit DAC (LSB-MSB)		
GC : DAC 1 : Trigger	10	discri_trigger_threshold	460	dac1
		10-bit DAC (LSB-MSB)		
GC : DAC 2 : Gain Sel.	10		470	dac2
		Enable 10-bit dual DAC power	_	
PP: 10-bit Dual DAC	1	pulsing	480	pwr_on_dual_dac
		Enable 10-bit dual DAC OTA		
PP: 10-bit Dual DAC OTA	1	power pulsing	481	pwr_on_ota_dual_dac
		Enable bandgap OTA power		
PP: Bandgap OTA	1	pulsing	482	pwr_on_bandgap
		Enable Delay cell power pulsing for		
PP: Delay (Start Ramp TDC)	1	the signal "start_ramp_tdc"	483	pwr_on_delay_start_ramp_tdc
		Delay for the "start_ramp_tdc"		
GC : Delay (Start Ramp TDC)	6	signal ( From MSB to LSB)	484	delay_start_ramp_tdc
	4	TDC ramp slope (fast = 0 or slow =	400	1 (6 1 . )
GC : TDC Ramp Slope	1	1)		sw_ramp_slope (fast or slow)
PP: TDC Ramp	1	Enable TDC ramp power pulsing	491	pwr_on_tdc_ramp
PP: ADC Discri	1	Enable ADC discri power pulsing	492	pwr_on_discri_adc
		Enable gain selection discri power		
PP: Gain Select Discri	1	1 0	493	pwr_on_discri_gs
GC : Auto Gain	1	Auto gain selection	494	sw_auto_gain_select
		Forces the gain value when auto		
GC : Gain Select	1	gain selection is OFF		gain_select (High Gain or Low Gain)
EC : ADC Ext Input	1	External ADC signal input	496	sw_in_adc_ext
		Switch for time signal charge signal	·	
		readout / high gain and low gain		
GC : Switch TDC On	1	charge	497	sw_tdc_on
		Allows to Mask Discriminator		
DM : Discriminator Mask	36	(channel 35 to 0)		mask_discri
EC: Hold Ext	1	Enable external hold_ext signal	534	cmd_hold_ext
PP: Discri Delay	1	Enable discri delay power pulsing	535	pwr_on_delay_discri
		Delay for the "trigger" signals (		
GC : Delay (Trigger)	6	From MSB to LSB)	<u>5</u> 36	delay_discri
DD: Discri 4-bit DAC Threshold		Discri 4-bit DAC – from channel 35		
Adjust	144	to 0 (from LSB to MSB)	542	dac_4_bit_theshold_adjust
		Fine (1) or coarse (0) adjustment on		
GC : Adjust 4-bit DAC	1	discri 4-bit DAC	686	sw_fine_adjust
PP: 4-bit DAC	1	Enable 4 bit dac power pulsing	687	pwr_on_dac4b
PP: Trigger Discriminator	1	Enable trigger discri power pulsing	688	pwr_on_discri
		Enable Delay cell power pulsing for		_
PP: Delay (ValidHold)	1	the "ValidHold" signal	689	pwr_on_delay_ValidHold
				-



		Delay for the "ValidHold" signal (		
GC : Delay (ValidHold)	6	From MSB to LSB)	690	delay_ValidHold (6 bits)
		Enable Delay cell power pulsing for		
PP: Delay (RstColumn)	1 the "RstColumn" signal		696	pwr_on_delay_RstColumn
		Delay for the "RstColumn" signal (		
GC : Delay (RstColumn)	6	From MSB to LSB)	697	delay_RstColumn (6 bits)
NC	2		703	
EC : End_ReadOut	1	Enable End_ReadOutX signals	705	
EC: Start_ReadOut	1	Enable Start_ReadOutX signals	706	
		Enable Opened collector ChipSat		
EC: ChipSat	1	signal	707	
		Enable Opened collector		
EC: TransmitOn2	1	TransmitOn2 signal	708	
		Enable Opened collector		
EC: TransmitOn1	1	TransmitOn1 signal	709	
		Enable Opened collector Dout2		
EC: Dout2	1	signal	710	
		Enable Opened collector Dout1		
EC: Dout1	1	signal	711	
Total	712		712	



# Probe register

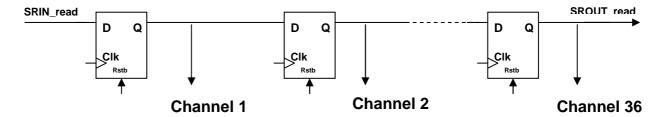


Labview Signal name	Probe	Comments	Probe output	Subadd
ExtraTrig (OR36)	1		Digital probe 1	0
Flag_TDC	1		Digital probe 2	1
Startb_ramp_ADC	1		Digital probe 2	2
Start_ramp_TDC	1		Digital probe 2	3
Out_PA_HG/Out_PA_LG	72	From channel 35 to 0	Analogue probe	4
Holdb_SCA	576	From channel 0 to 35 and from column 0 to 15	Digital probe 2	76
Out_ADC_Discri	36	From channel 0 to 35	Digital probe 2	652
Out_Gain_Select_Discri	36	From channel 0 to 35	Digital probe 2	688
Threshold	36	From channel 35 to 0	Analogue probe	724
Out_fs	36	From channel 0 to 35	Analogue probe	760
Out_t_delayed	36	From channel 35 to 0	Digital probe 1	796
Out_t	36	From channel 0 to 35	Digital probe 1	832
Start_ramp_TDC	1		Digital probe 2	868
Start_ramp_TDC_delayed	1		Digital probe 2	869
Out_ramp_TDC	1		Analogue probe	870
Rst_SCA/Rst_SCA_delayed	32	From column 0 to15	Digital probe 2	871
ValidHold/ValidHold_delayed	32	From column 0 to15	Digital probe 2	903
Read	16	From column 0 to15	Digital probe 2	935
NC	1		none	951
Total	952			952



# 14 Multiplexed output "Read registers"

Read register (multiplexed analog output)



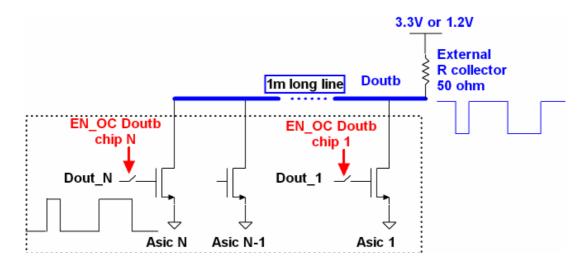
SPIROC1/2 Analogue output Truth Table

SC: ADC Ext Input	SC: Flag TDC Ext	Pin: Flag TDC Ext	SC: Switch TDC	SC: AutoGain	SC: GainSelect	OUTPUT
0	0	X	X	X	X	managed by Digital ASIC (Flag TDC Int)
0	1	0	0	X	X	TDC Ramp
0	1	0	1	X	X	High Gain
0	1	1	0	0	X	depends on GainSelect Discriminator
0	1	1	0	1	0	High Gain
0	1	1	0	1	1	Low Gain
0	1	1	1	X	X	Low Gain
1	X	X	X	X	X	ADC Ext Input

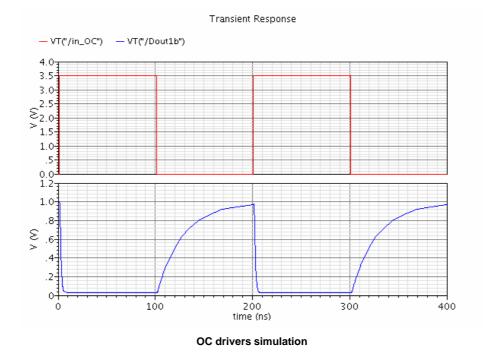


### 15 Digital open-collectors outputs/inputs

Dout1b, Dout2b, TransmitOn1b, TransmitOn2b, Chipsatb are open collector signals.



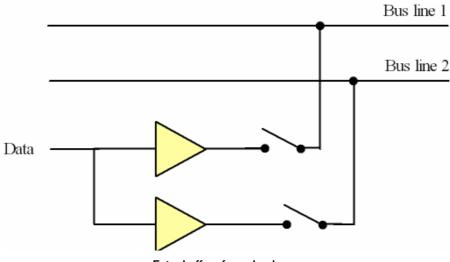
Big internal drivers (Ron=a few ohms) are integrated for each signal to output them on a 5m long line and with an external resistor of 50  $\Omega$ . The Figure 17 exhibits a simulation with a 5 m long line (equivalent to 500 pF), Rcollector=50 $\Omega$ , vdd=1.2V.



### Redundancy of the OC lines:

To ensure the realibility of the lines used in the daisy chain, the Doutb, transmitonb, start and end readout signals have been doubled. The selection of the line to be daisy chained is made using SC parameters.



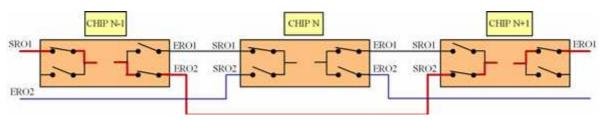


Extra buffers for redundancy

# StartReadout and EndReadout bypass:

The bypass of one bad ASIC of the daisy chain can be performed as the StartRO and EndReadout signals have been doubled.

The bypass has to be made on the PCB using switches or resistors. The selection of the line is made using the SC parameters.



StartReaout and EndReaout bypass



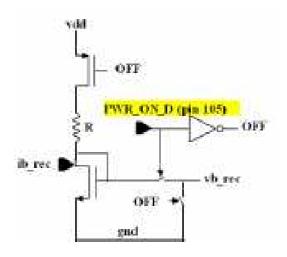


#### 16 Power pulsing signals

The new electronics readout is intended to be embedded in the detector. One important feature is the reduction of the power consumption. The huge number of electronic channels makes crucial such a reduction to  $25~\mu Watt$  per channel using the power pulsing scheme, possible thanks to the ILC bunch pattern: 2~ms of acquisition, conversion and readout data for 198~ms of dead time. However, to save more power, during each mode, the unused stages are off.

- **pwr\_on\_a**: analog part (preamplifiers, slow shapers, fast shapers, trigger discriminators, tdc ramp)
- pwr\_on\_sca : sca part
- **pwr\_on\_adc**: conversion part (gain selection discriminators, adc discriminators, adc ramp), output analog buffers.
- pwr\_on\_dac : Bandgap, 10-bit dual DAC
- pwr\_on\_d: digital part

Bias currents interrupted (see slow control parameters) during interbunch (see figure below).

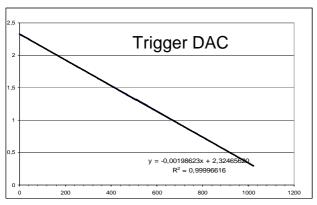


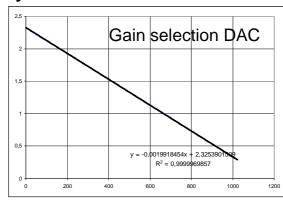


# 17 Trigger and gain selection DAC linarity measurement Threshold DAC $\,$

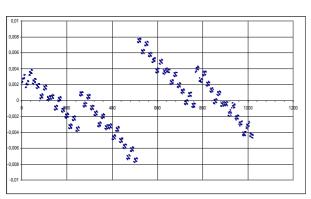
Their linearity have been measured: the residuals of the both DACs are within  $\pm 5$  mV for a 2.6V dynamic range which corresponds to an Integral Non Linearity of 0.2% (2LSB). The slope is 2.5mV per DAC unit.

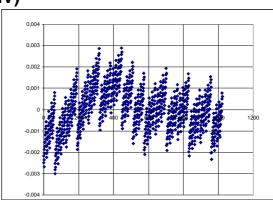
# Linearity





# Residuals (mV)

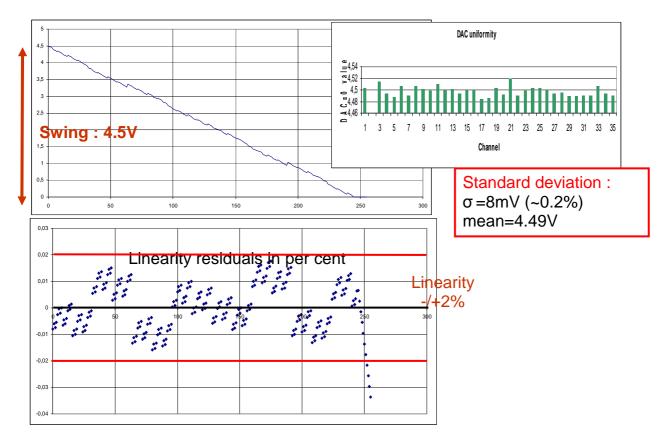




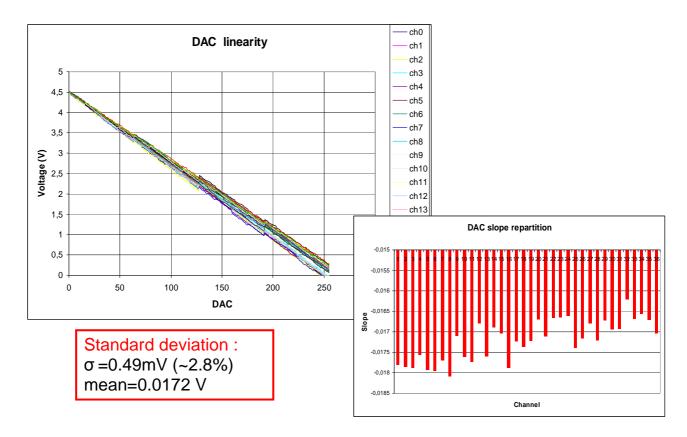


#### 18 Input 8-bit DAC linarity measurements

The input DAC span goes from 4.5V down to 0.5V with a LSB of 20 mV. The default value is 4.5V in order to operate the SiPM at minimum over-voltage when the DAC is not loaded. The linearity is  $\pm 2\%$  (5LSB), just enough for the SiPM operation but consistent with the allocated area. Also, the dispersion between channels, although not fundamental could also be improved. The power dissipation is well within the specs and the 100nA bias current to  $V_{dd}$  makes the chip difficult to measure without special precautions.



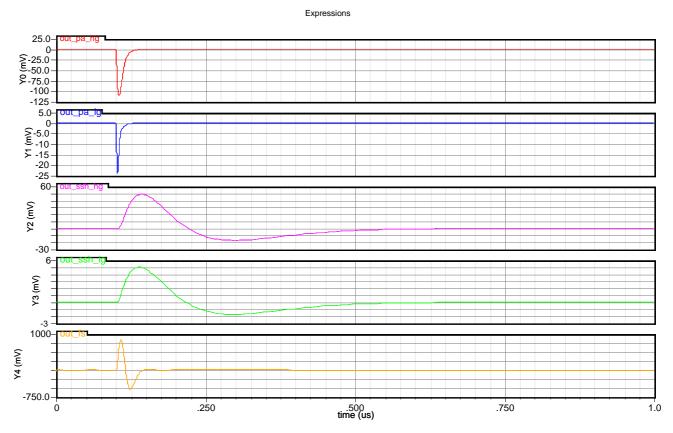


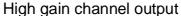


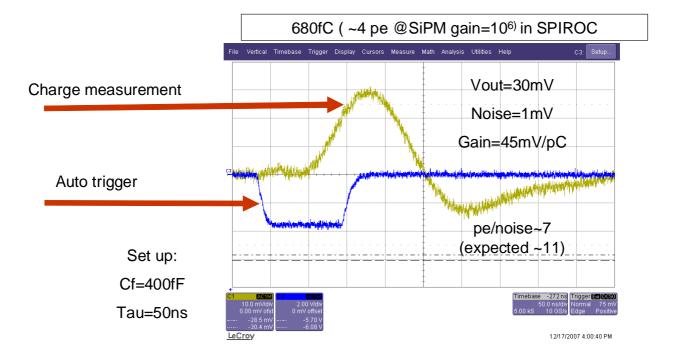


# 19 Charge output Temporal signals

User: raux Date: Jan 8, 2008 Time: 3:16:24 PM CET

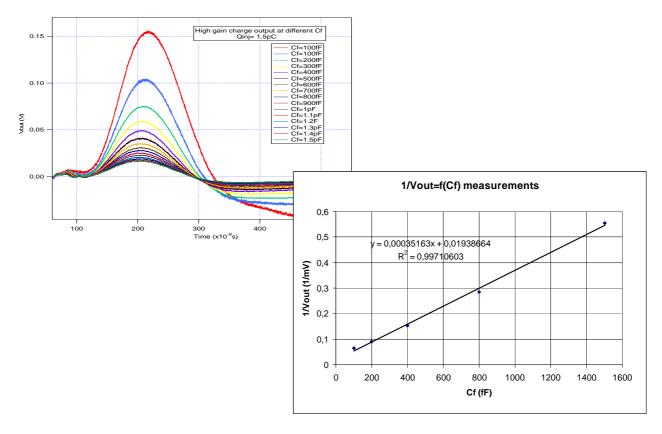


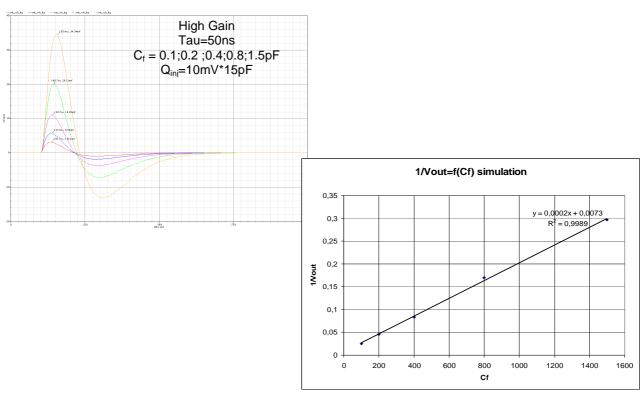




- High gain output







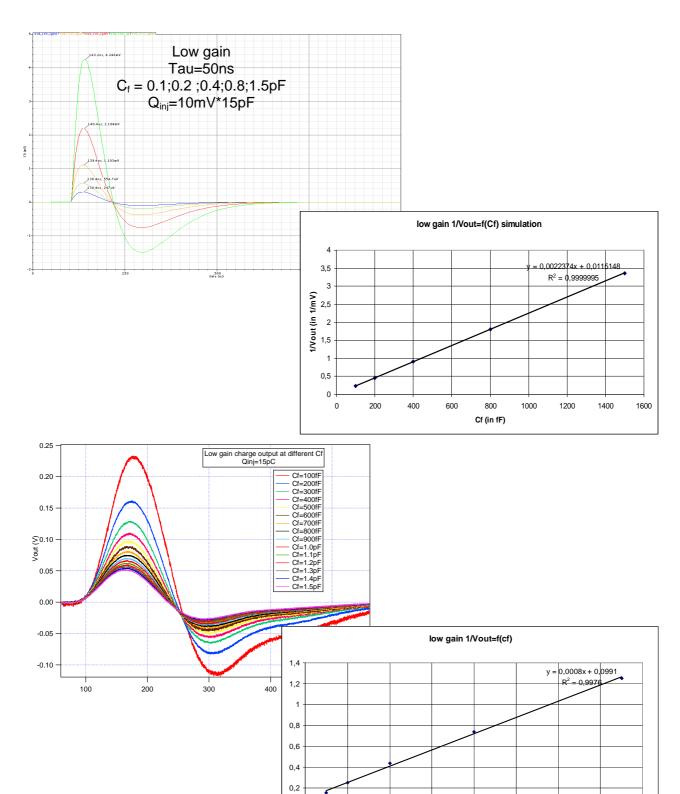
- Low gain output



1200

1400

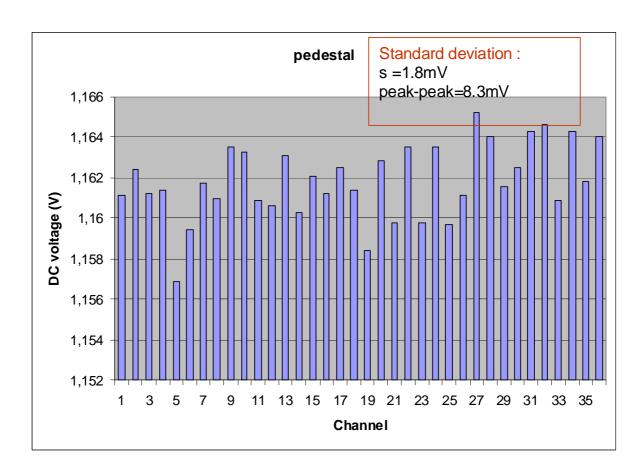
1600



0 +

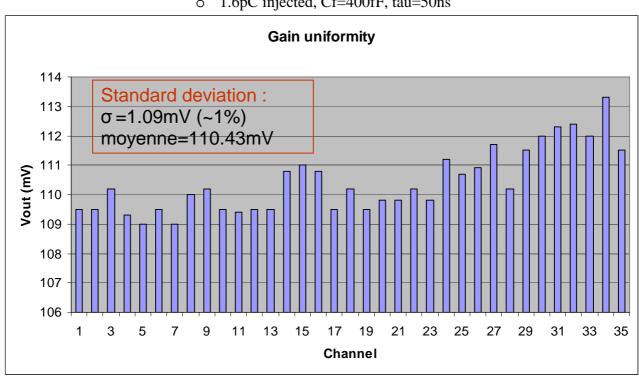


#### **Pedestals mesurements**



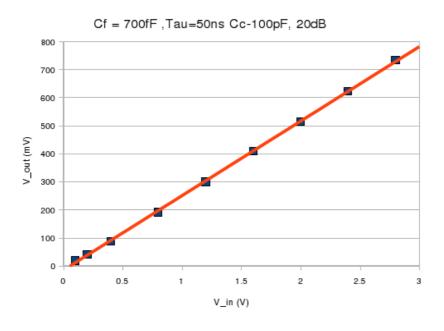
# Gain uniformity measurement





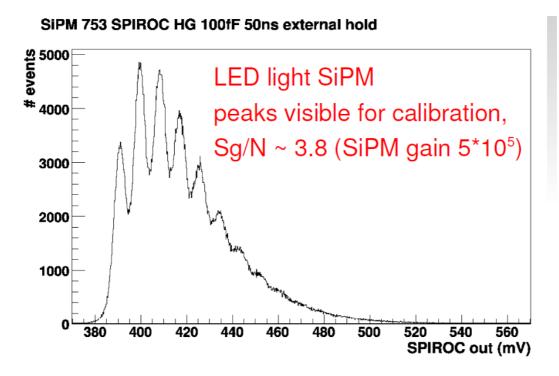


# Linearity



#### Single photo electron spectrum:

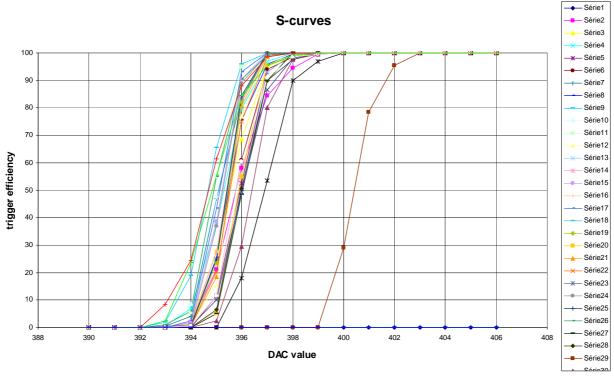
The photoelectron to noise ratio of 4 allows to nicely resolve the single photoelectrons peaks. The next figure shows the single photo electron spectrum.

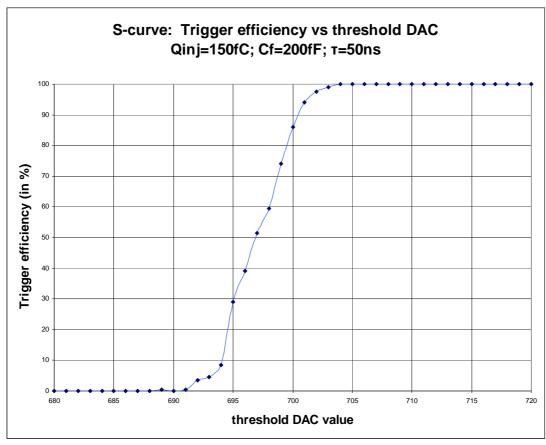


# **20** Trigger measurements S-curves

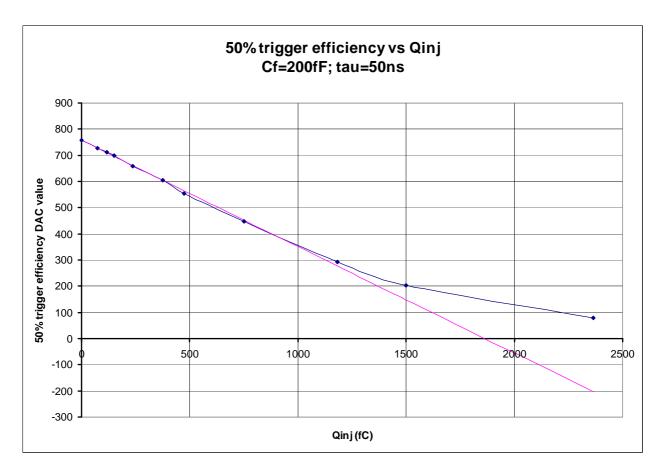
o Cf=400fF, Qinj=150fC, tau=50ns





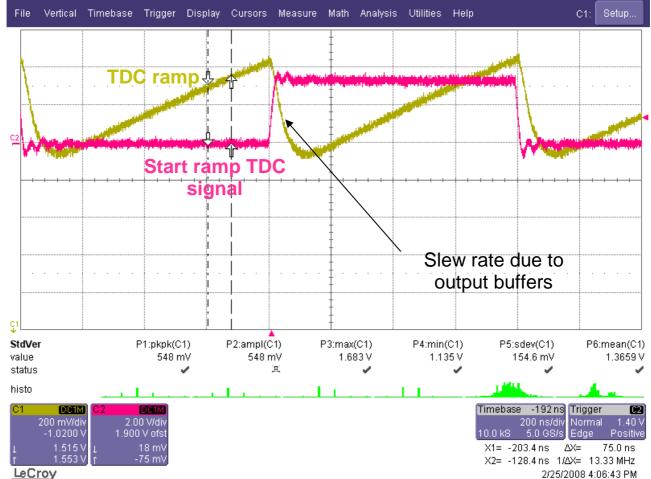








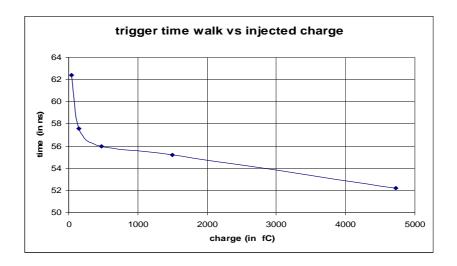






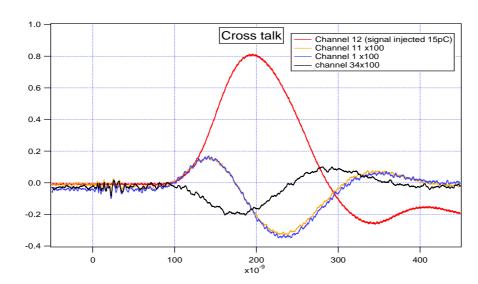
#### • Trigger Time walk:

o The trigger time walk between large signal and small signal is about 6ns



### • Charge output Cross-talk

o Very low Cross-Talk: 0.3% (long distance cross talk due to slow shaper voltage reference: If this voltage decoupled with  $100\mu F$ , it becomes negligible  $\sim 0.04\%$ )





# 21 Digital parts

